Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/552,353	INOUE ET AL.	
Examiner	Art Unit	
Ronald W. Leja	2836	

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Class	Subclass	Date	Examiner		
361	119	3/7/2007	RWL		
361	127	3/7/2007	RWL		
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INTERFERENCE SEARCHED			
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